Special Issue

Applied System Innovations Using Recent Graph-Based Artificial Intelligence Techniques

Message from the Guest Editor

In recent years, graph-based artificial intelligence techniques, e.g., graph embedding and graph neural networks (GNNs), have become the frontier of artificial intelligence and data science research, showing state-of-the-art performance in various applications. [...] This Special Issue focuses on the applied system innovations, as well as the successful applications of graph-based artificial intelligence techniques in a wide range of engineering fields. Topics of interest include but are not limited to:

- Graph-based innovations for industrial and control systems, e.g., model predictive control;
- Graph-based innovations for financial applications, e.g., stock market prediction;
- Graph-based innovations for communication networks, e.g., intrusion detection, mobile traffic prediction;
- Graph-based innovations for transportation applications, e.g., road traffic prediction, traffic data imputation;
- Graph-based innovations for electronic commerce applications, e.g., recommendation systems, fraud detection;
- Other relevant innovations with graph-based artificial intelligence methods.

Guest Editor

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